

Search Notes**Application/Control No.**

09/757,006

Examiner

Le Nguyen

Applicant(s)/Patent under Reexamination

GEIER ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	769	11/22/2005	LVN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PGPub; USPAT: 707/104.1	11/22/2005	LVN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner